

# Supplementary Materials: Surface-Bound and Volatile Mo Oxides Produced During Oxidation of Single MoS<sub>2</sub> Crystals in Air and High Relative Humidity

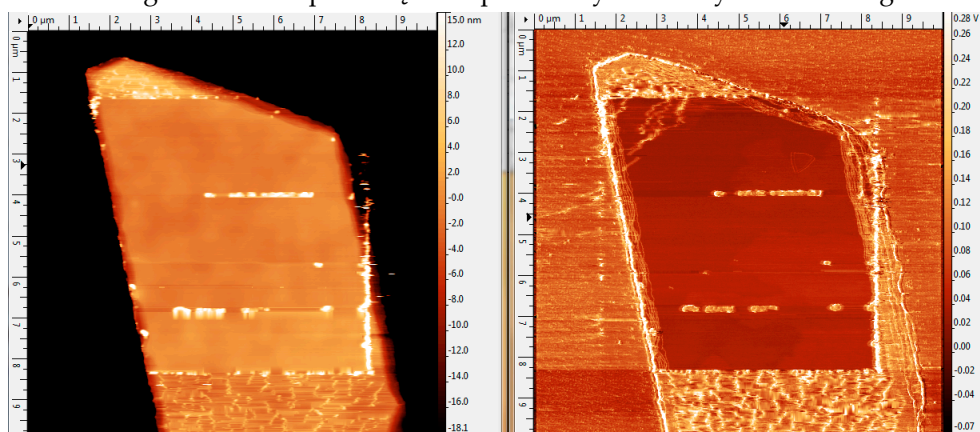
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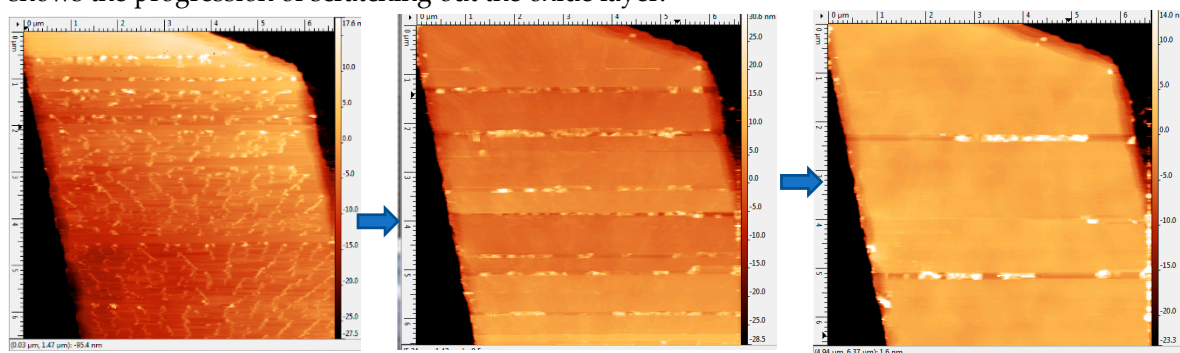
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Below, we produce several more examples of scratching out a thin oxide layer during contact-mode AFM scanning at room temperature from previously thermally oxidized single MoS<sub>2</sub> flakes.



**Figure S1.** An example of creating ripples and scratching out an already fragmented oxide layer (due to extensive heating). Left: topography; Right: twice the uncalibrated friction.

AFM contact mode imaging, 10 μm by 10 μm. In the central zone of the MoS<sub>2</sub> flake heated extensively at 350 °C 6.6 μm by 6.6 μm area has been scratched out at room temperature. Figure S2 shows the progression of scratching out the oxide layer.



**Figure S2.** Progression of the process of removing already loosely bound oxides from the flake in Figure S1. Presented are 6.6 μm by 6.6 μm AFM contact mode topography images.



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